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# Signal Processing, Sensor Fusion, and Data Fusion in Measurement Systems

Guest Editor:

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Deadline for manuscript submissions:

30 June 2024

## **Message from the Guest Editor**

This Special Issue invites papers presenting innovative works on all aspects related to fusion in measurement systems, especially in the areas: sensor level fusion, data fusion methods, application of fusion in measurement systems, data fusion in WIM systems, multi-sensor data fusion, signal processing in measurement systems.

The topic included but was not limited in:

- data fusion
- information fusion
- data fusion in WIM
- sensor fusion
- signal processing
- measurement systems
- fusion methods
- data fusion applications
- multi-sensor fusion
- sensor networks
- vehicle sensor fusion
- robot sensor fusion
- sensor fusion algorithms
- smart sensors
- applications of sensor fusion
- multimodal sensor fusion











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### **Editor-in-Chief**

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## **Message from the Editor-in-Chief**

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